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Semiconductor devices - Micro-electromechanical devices - Part 20: Gyroscopes

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 01/15

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EUROPEAN STANDARD

NORME EUROPÉENNE

EUROPÄISCHE NORM

EN 62047-20

September 2014

ICS 31.080.99

English Version

Semiconductor devices - Micro-electromechanical devices - Part 20: Gyroscopes (IEC 62047-20:2014)

Dispositifs à semiconducteurs - Dispositifs microélectromécaniques - Partie 20: Gyroscopes (CEI 62047-20:2014)

Halbleiterbauelemente - Bauelemente der Mikrosystemtechnik - Teil 20: Gyroskope (IEC 62047-20:2014)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

Ref. No. EN 62047-20:2014 E

Foreword

The text of document 47F/188/FDIS, future edition 1 of IEC 62047-20, prepared by SC 47F “Microelectromechanical systems” of IEC/TC 47 “Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62047-20:2014.

The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2015-04-30
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2017-07-31

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IEC 62047-20

Edition 1.0 2014-06

INTERNATIONAL STANDARD

NORME INTERNATIONALE

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Dispositifs à semiconducteurs – Dispositifs microélectromécaniques – Partie 20: Gyroscopes

IEC 62047-20:2014-06(en-fr)

IEC 62047-20

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Semiconductor devices – Micro-electromechanical devices – Part 20: Gyroscopes

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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FOREWORD

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International Standard IEC 62047-20 has been prepared by subcommittee 47F: Micro-electromechanical systems, of IEC 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47F/188/FDIS	47F/191/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62047 series, published under the general title *Semiconductor devices – Micro-electromechanical devices*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 20: Gyroscopes

1 Scope

This part of IEC 62047 specifies terms and definitions, ratings and characteristics, and measuring methods of gyroscopes.

Gyroscopes are primarily used for consumer, general industries and aerospace applications. MEMS and semiconductor lasers are widely used for device technology of gyroscopes.

Hereafter, gyroscope is referred to as gyro.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

None